N-Channel Power MOSFET 500 V, 2.7 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V _{DSS}	500	V
Continuous Drain Current R _{0JC}	I _D	3.0	Α
Continuous Drain Current $R_{\theta JC}$, $T_A = 100^{\circ}C$	I _D	1.9	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	12	Α
Power Dissipation $R_{\theta JC}$	P _D	61	W
Gate-to-Source Voltage	V _{GS}	±30	٧
Single Pulse Avalanche Energy, I _D = 3.4 A	E _{AS}	120	mJ
ESD (HBM) (JESD22-A114)	V _{esd}	2800	V
Peak Diode Recovery	dv/dt	4.5 (Note 1)	V/ns
Continuous Source Current (Body Diode)	I _S	3.4	Α
Maximum Temperature for Soldering Leads	TL	260	°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1

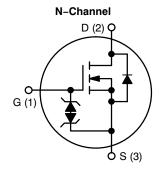
1. $I_D \le 3.4 \text{ A}$, $di/dt \le 200 \text{ A/}\mu\text{s}$, $V_{DD} \le BV_{DSS}$, $T_{.1} \le 150^{\circ}\text{C}$.



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http://onsemi.com

V _{DSS}	R _{DS(on)} (MAX) @ 1.5 A
500 V	2.7 Ω







IPAK CASE 369D STYLE 2

DPAK CASE 369AA STYLE 2

MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

THERMAL RESISTANCE

Parameter			Value	Unit
Junction-to-Case (Drain)	NDD04N50Z	$R_{ heta JC}$	2.0	°C/W
Junction-to-Ambient Steady State	(Note 3) NDD04N50Z (Note 2) NDD04N50Z-1	$R_{ heta JA}$	40 80	

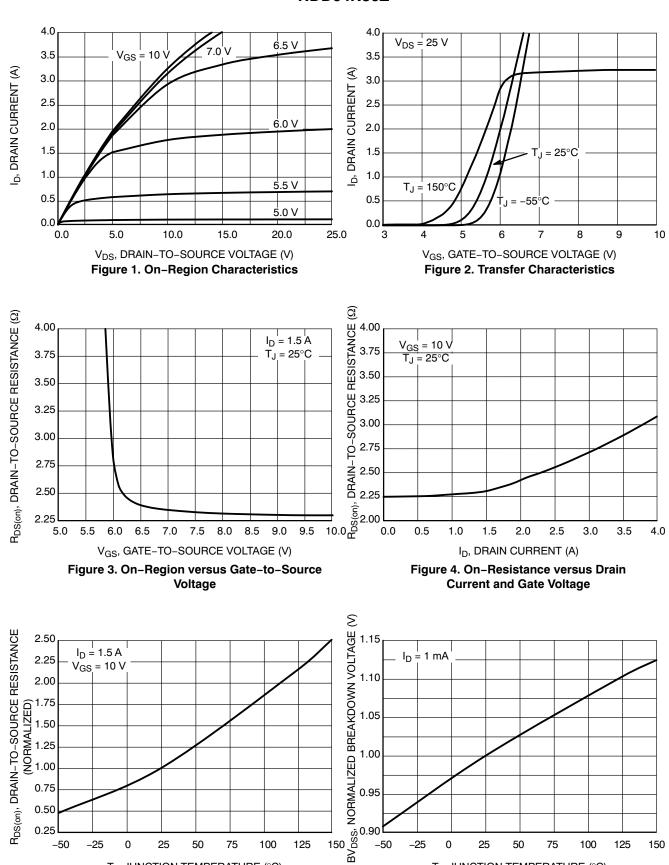
^{2.} Insertion mounted

ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise noted)

Characteristic	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF CHARACTERISTICS			•		•		
Drain-to-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		500			V
Breakdown Voltage Temperature Coefficient	ΔBV _{DSS} / ΔΤ _J	Reference to 25°C, I _D = 1 mA			0.6		V/°C
Drain-to-Source Leakage Current	I _{DSS}	.,	25°C			1.0	μΑ
	V _{DS} = 500 V, V _{GS} = 0 V			50			
Gate-to-Source Forward Leakage	I _{GSS}	V _{GS} = ±20 V				±10	μΑ
ON CHARACTERISTICS (Note 4)		,			,		,
Static Drain-to-Source On-Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 1.5	5 A		2.3	2.7	Ω
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 50$	μΑ	3.0		4.5	V
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 1.5	5 A		2.1		S
DYNAMIC CHARACTERISTICS		•				•	
Input Capacitance (Note 5)	C _{iss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		246	308	370	pF
Output Capacitance (Note 5)	C _{oss}			33	43	53]
Reverse Transfer Capacitance (Note 5)	C _{rss}			7.0	9.0	11	
Total Gate Charge (Note 5)	Qg	V _{DD} = 250 V, I _D = 3.4 A, V _{GS} = 10 V		6.0	12	18	nC
Gate-to-Source Charge (Note 5)	Q _{gs}			1.3	2.6	4.0	
Gate-to-Drain ("Miller") Charge (Note 5)	Q _{gd}			3.5	6.1	7.0	1
Plateau Voltage	V _{GP}	1			6.6		٧
Gate Resistance	R_g			1.8	5.4	16.2	Ω
RESISTIVE SWITCHING CHARACTERISTI	cs	•				•	
Turn-On Delay Time	t _{d(on)}				9.0		ns
Rise Time	t _r	V _{DD} = 250 V, I _D = 3.4	1 A,		9.0		
Turn-Off Delay Time	t _{d(off)}	V_{GS} = 10 V, R_{G} = 5 Ω			16		1
Fall Time	t _f				10		1
SOURCE-DRAIN DIODE CHARACTERIST	ICS (T _C = 25	°C unless otherwise noted)					
Diode Forward Voltage	V _{SD}	I _S = 3.4 A, V _{GS} = 0	V			1.6	V
Reverse Recovery Time	t _{rr}	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 3.4 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$			240		ns
Reverse Recovery Charge	Q _{rr}				0.9		μC

Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
 Guaranteed by design.

^{3.} Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).



T.J., JUNCTION TEMPERATURE (°C) Figure 5. On-Resistance Variation with **Temperature**

50

75

100

125

25

0.25

-50

-25

T.I. JUNCTION TEMPERATURE (°C) Figure 6. BV_{DSS} Variation with Temperature

50

75

100

125

150

25

-50

-25

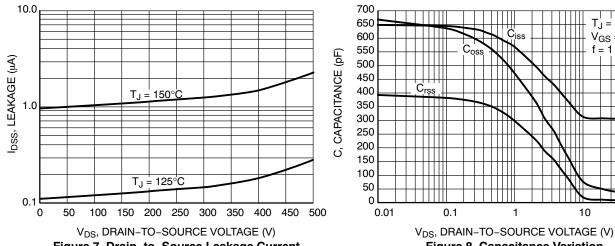


Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation

f = 1 MHz

100

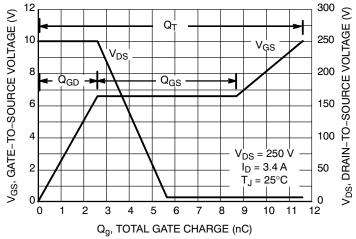


Figure 9. Gate-to-Source Voltage and Drain-to-Source Voltage versus Total Charge

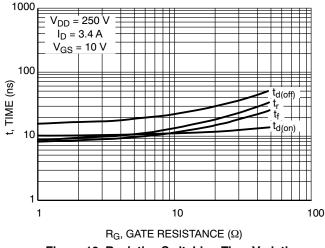


Figure 10. Resistive Switching Time Variation versus Gate Resistance

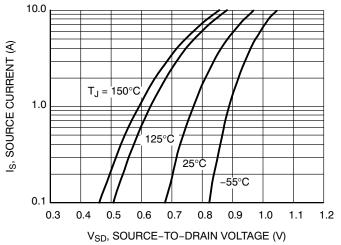


Figure 11. Diode Forward Voltage versus Current

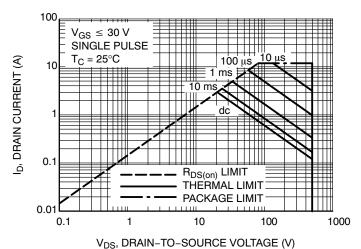


Figure 12. Maximum Rated Forward Biased Safe Operating Area NDD04N50Z

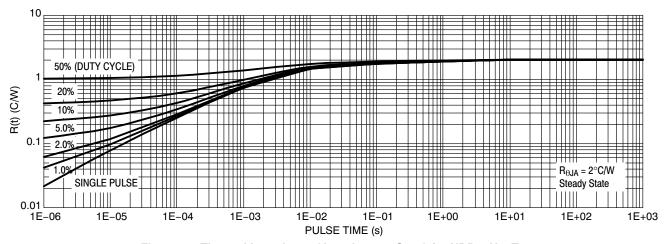


Figure 13. Thermal Impedance (Junction-to-Case) for NDD04N50Z

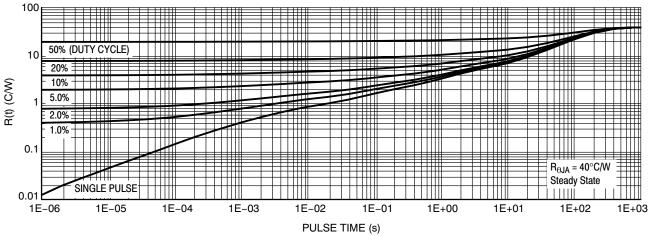


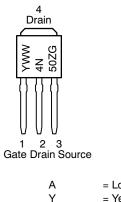
Figure 14. Thermal Impedance (Junction-to-Ambient) for NDD04N50Z

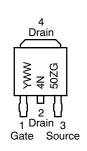
ORDERING INFORMATION

Order Number	Package	Shipping [†]
NDD04N50Z-1G	IPAK (Pb-Free)	75 Units / Rail
NDD04N50ZT4G	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MARKING DIAGRAMS





 A
 = Location Code

 Y
 = Year

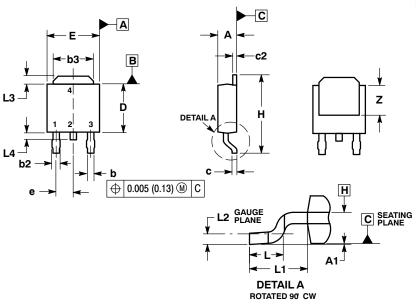
 WW
 = Work Week

 G
 = Pb-Free Package

PACKAGE DIMENSIONS

DPAK (SINGLE GUAGE)

CASE 369AA-01 **ISSUE B**



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: INCHES.

 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS b3, L3 and Z.

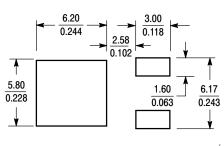
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A 1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
U	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
Е	0.250	0.265	6.35	6.73	
е	0.090 BSC		2.29 BSC		
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	REF	2.74 REF		
L2	0.020 BSC		0.51	BSC	
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
z	0.155		3.93		

SOLDERING FOOTPRINT*



 $\left(\frac{\text{mm}}{\text{inches}}\right)$ SCALE 3:1

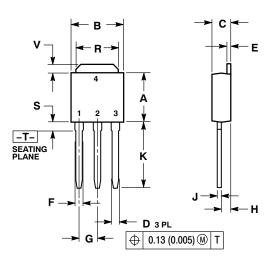
STYLE 2:

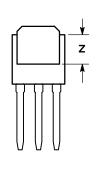
PIN 1. GATE
2. DRAIN
3. SOURCE
4. DRAIN

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

IPAK CASE 369D-01 ISSUE B





- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
V	0.035	0.050	0.89	1.27
Z	0.155		3.93	

STYLE 2: PIN 1. GATE

- 2 DRAIN
- 3. SOURCE
- 4. DRAIN

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